

Home | Login | Logout | Access Information | Alerts |

## **Welcome United States Patent and Trademark Office**

Search Results			BROWSE SEAR		SEARCH	CH IEEE XPLORE GUIDE		
Your search	"((((((edge or contour) <in n matched 123 of 28536 doo n of 100 results are displaye</in 	cuments.					<b>्रि</b> ट-मध्ये	
» Search Options		Modif	Modify Search					
View Session History		(((((ec	((((((edge or contour) <in>metadata))<and>((edge or contour or border or outline)<in></in></and></in>					
New Search		<b>☑</b> cı	neck to search onl	y within this I	results set			
		Displa	Display Format:   Citation C Citation & Abstract					
» Key								
IEEE JNL	IEEE Journal or Magazine	t view	selected items	Select All	Deselect Ali		View: 1-25   <u>26-5</u>	
IEE JNL	IEE Journal or Magazine	П	1. Toward edge	sharpening:	a SAR speckle	e filtering algori	ithm	
IEEE CNF	IEEE Conference Proceeding		Domg, Y.; Miln	ne, A.K.; forst	er, B.C.;			
IEE CNF	IEE Conference Proceeding		Volume 39, Is	sue 4, April :	<u>ensing, IEEE Tra</u> 2001 Page(s):85 I 109/36.917910			
IEEE STD	IEEE Standard		AbstractPlus   Rights and Per		Full Text: <u>PDF</u> (	376 KB) IEEE	JNL	
			Vacuum Nano International 11-16 July 200 Digital Object I	; Davidson, J electronics C 04 Page(s):15 Identifier 10.1 Full Text: <u>PC</u>	I.L.; Kang, W.P.; conference, 2004	Wisitsora-at, A. 1. IVNC 2004. To	; Kerns, D.V.; echnical Digest of th	
			18-20 Dec. 20 Digital Object	/ang Zhengm aphics, 2004, 04 Page(s):2 Identifier 10.1 Full Text: <u>PC</u>	iing; . Proceedings, T	hird Internationa	sion al Conference on	
			Volume 153, I	, Y.L.; Kassin and Signal P Issue 2, 6 Ap Identifier 10.	n, A.A.; <u>Processing, IEE F</u> pril 2006 Page(s 1049/ip-vis:2005	Proceedings- ):215 - 223		
		П	5. A nonlinear P	DE based e	dge detection f	or Image meas	urement	

Shujun Fu; Qiuqi Ruan; Wenqia Wang;

Control and Automation, 2005, ICCA '05, International Conference on

Volume 2, 26-29 June 2005 Page(s):1028 - 1033 Vol. 2 Digital Object Identifier 10.1109/ICCA.2005.1528273